NOTES:

- 1. SUBSTRATE FUSED SILICA
- 2. SURFACE S2 TO BE PARALLEL TO SURFACE S1 TO WITHIN <3 ARCMIN
- 3. COATING (APPLY ACROSS COATING APERTURE):

\$1: R(ABS) > 99.8% @ 1064nm @ 0 - 45° AOI

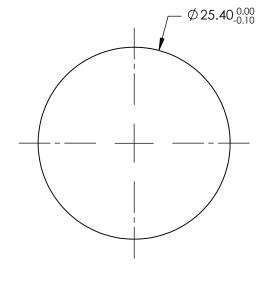
DAMAGE THRESHOLD, PULSED 15 J/cm^2 @ 1064nm, 20ns, 20Hz

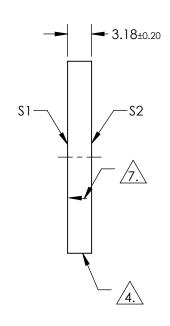
S2: NONE



- POWER, IRREGULARITY, AND SURFACE QUALITY SPECIFICATIONS APPLY ACROSS CLEAR APERTURE
- 6. CLEAR APERTURE AND COATING APERTURE ARE CENTERED ON SURFACES

APPLY ARROW ON EDGE WITH LASER ETCH, PENCIL, OR PERMANENT INK POINTING TOWARDS SURFACE \$1





FOR INFORMATION ONLY: DO NOT MANUFACTURE PARTS TO THIS DRAWING

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE DIMENSIONS ARE FOR REFERENCE ONLY

SHAPE	\$1 PLANO	S2 PLANO			8	Edmund Option	CS®
SURFACE QUALITY	10-5	GROUND	THIRD ANGLE PROJECTION		TITLE	25.4mm DIA., 3.18mm THICK, 1064nm 0-45°, Nd:YAG LASER LINE MIRROR	
SURFACE FLATNESS	0.10 WAVE	N/A					
MIN CLEAR APERTURE	Ø20.32	N/A				ria. III to El toEll El le IVIII (Coll	CHEET
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED	ALL DIMS IN	mm	DWG NO	14340	SHEET 1 OF 1